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FIG. 1

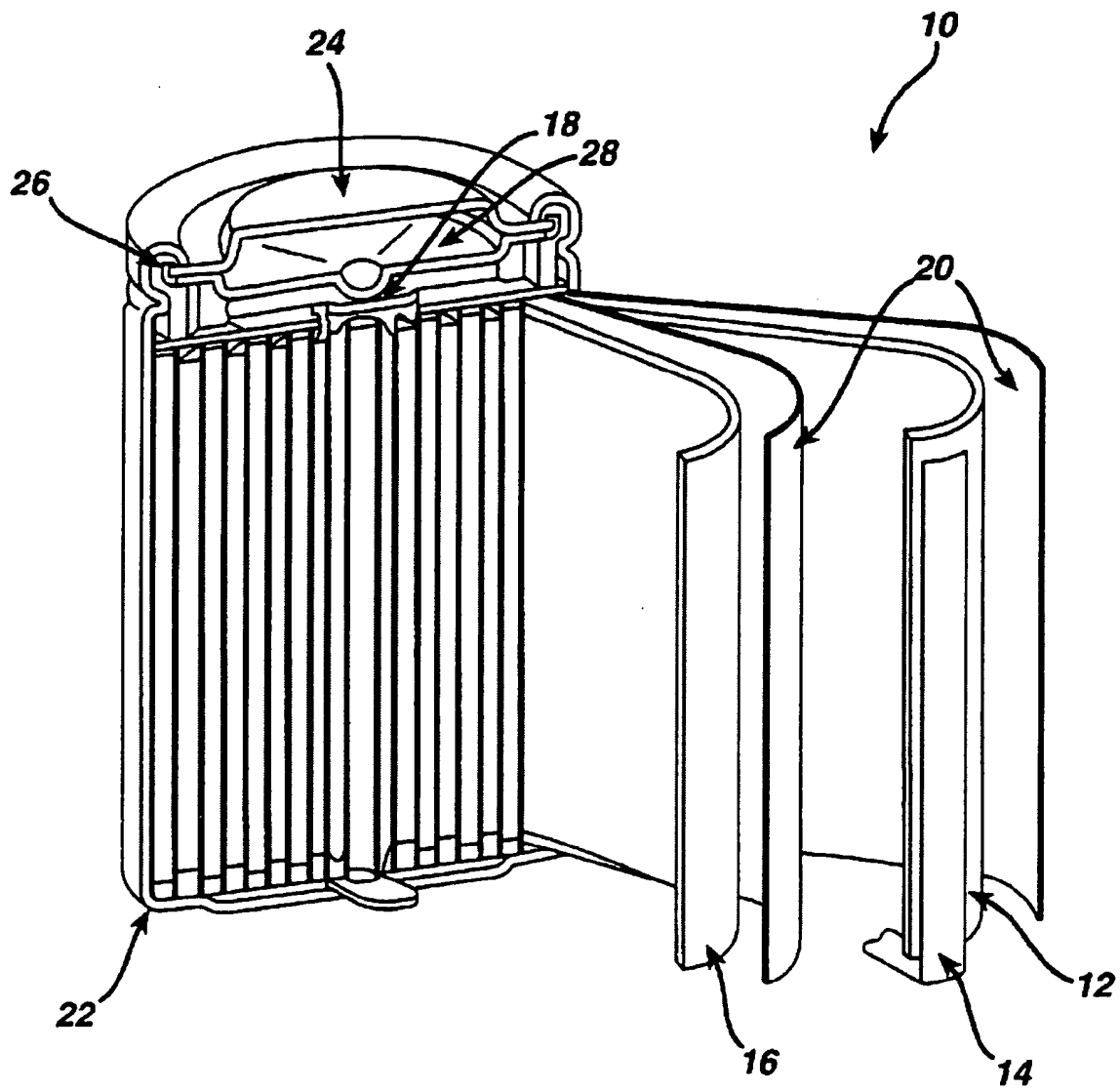


FIG. 1

The figure displays three stacked X-ray diffraction (XRD) patterns. The y-axis represents Intensity in Counts, ranging from 0 to 4500. The x-axis represents the diffraction angle 2θ in degrees, ranging from 10 to 70. The top pattern, labeled λ-MnO₂, 16 hrs, shows a very sharp and intense peak at approximately 18.8° 2θ, with other peaks at higher angles. The middle pattern, labeled λ-MnO₂, 0.75 hrs, shows a similar profile but with a slightly less intense peak at 18.8° and more visible peaks at higher angles. The bottom pattern, labeled LiMn₂O₄ spinel, shows a distinct set of peaks, with the most intense peak at approximately 44.7° 2θ. A reference pattern for LiMn₂O₄ spinel is shown at the bottom with small vertical tick marks.

FIG. 2

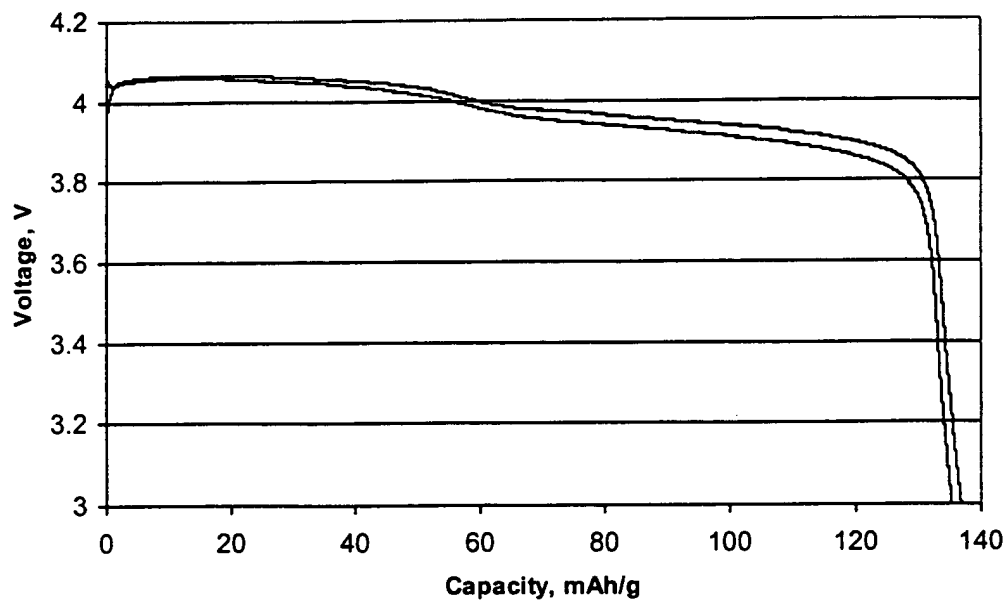


FIG. 3

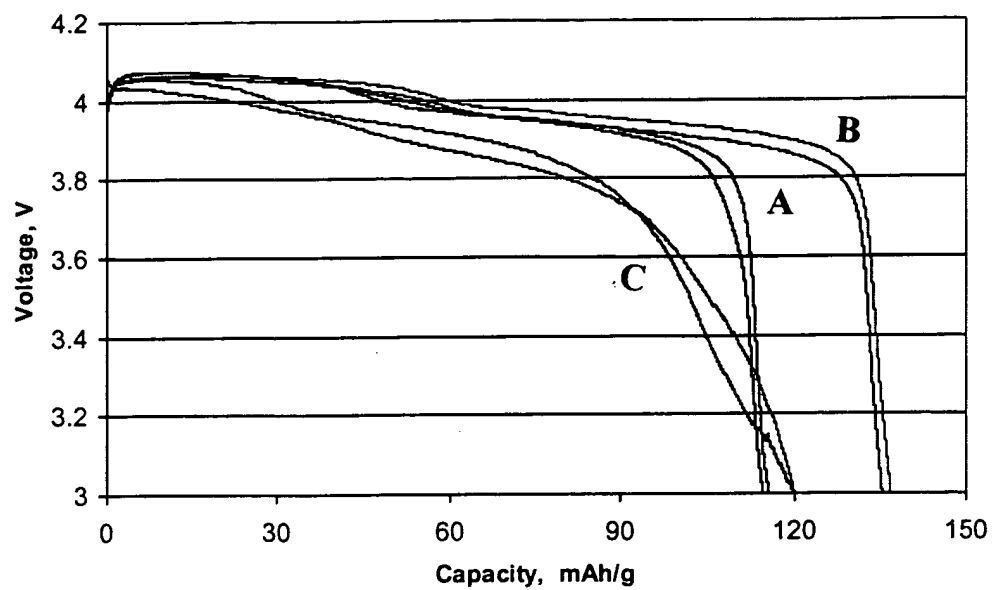


FIG. 4

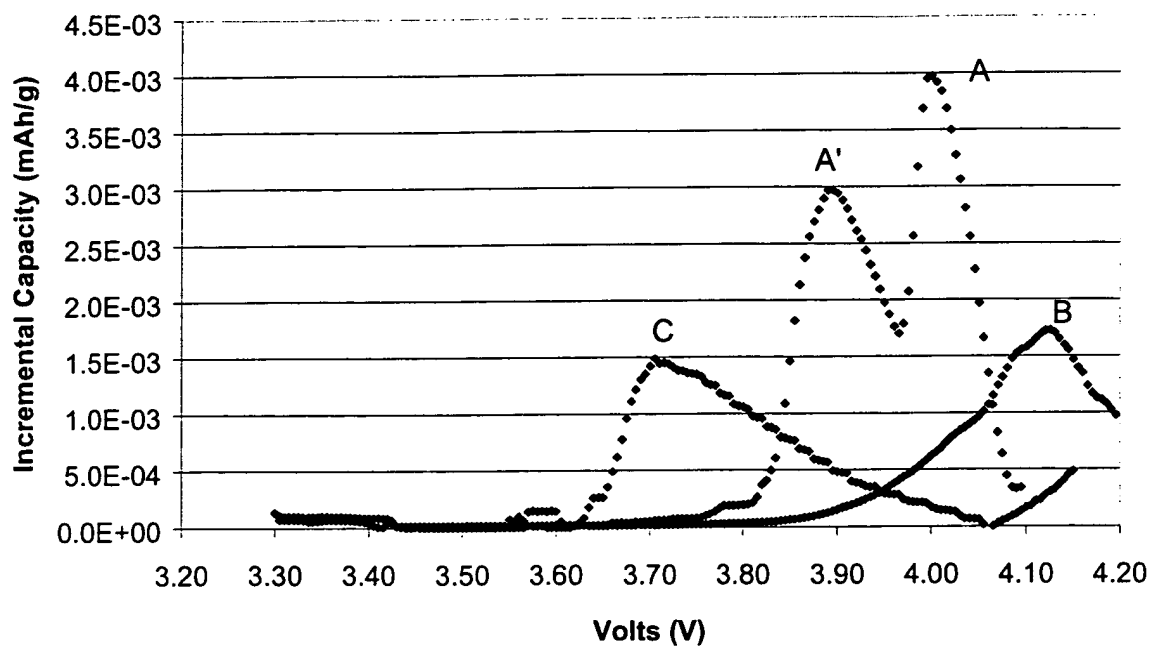


FIG. 5

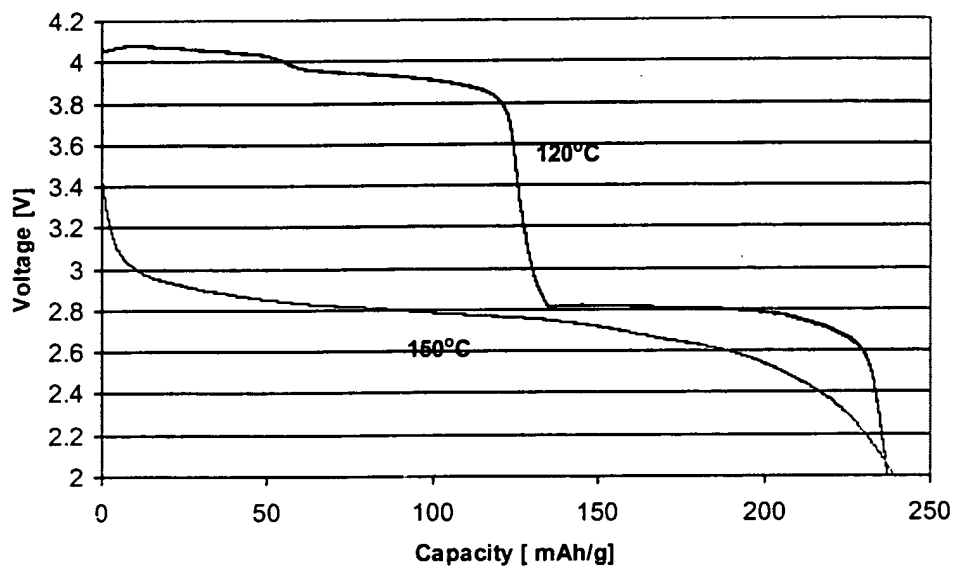


FIG. 6